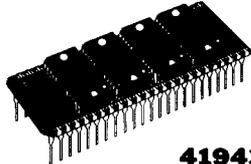


MH25616PNA-10,-12



4194304-BIT(262144-WORD BY 16-BIT)PSEUDO-PSEUDO STATIC RAM

DESCRIPTION

The MH25616PNA is 262144 word x 16 bit PSEUDO-PSEUDO static RAM and consist of four industry standard 256K x 4 bit dynamic RAMs in SOJ, two data selector in SOP and one DRAM controller in SOP. The mounting of SOJ and SOP on a dual in-line package provides any application where high densities and large quantities of memory are required.

FEATURES

Type	Access time (max) Note 1	Power dissipation (typ)
MH25616PNA-10	136ns	750mW
MH25616PNA-12	156ns	650mW

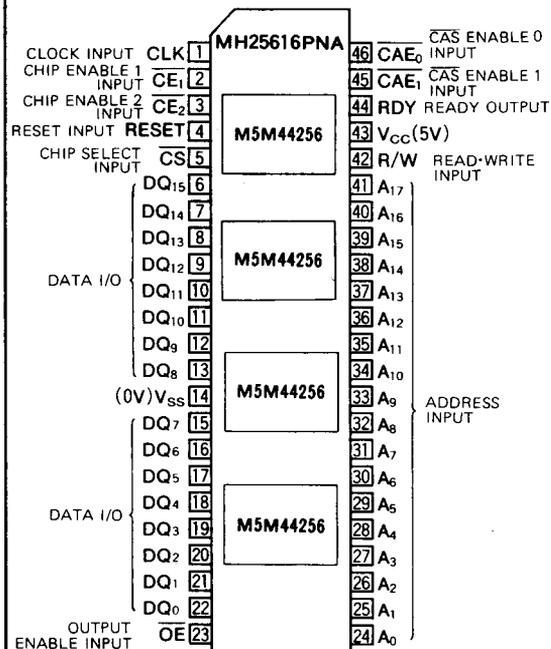
Note 1: When No-wait operation, Access time is measured from end of T1 of clock.

- Single +5V (±10%) supply operation
- 46 pin 600 mil Dual in-line package
- No Refresh
- All inputs and outputs are directly TTL compatible
- Includes (0.22µF x 7) decoupling capacitors

APPLICATION

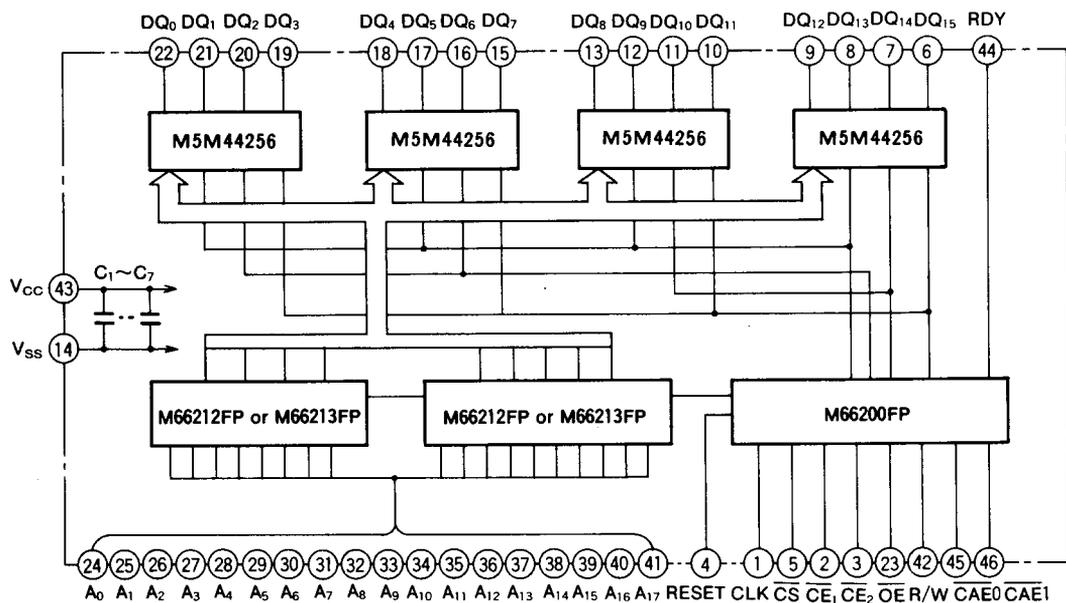
Small Capacity Memory Units

PIN CONFIGURATION (TOP VIEW)



Outline 46N1

BLOCK DIAGRAM



4194304-BIT(262144-WORD BY 16-BIT)PSEUDO-PSEUDO STATIC RAM

FUNCTION

MH25616PNA series is 262144 word by 16-bit. These devices operate on a single 5V supply, and all inputs and outputs are directly TTL compatible.

When DRAM controller counted 117th clock pulse from CLK terminal, DRAM is automatically refreshed. Accordingly, Outside refreshing is not required.

Multiplexer enable to put separate address in as SRAM.

Internal action of the MH51208PNA is of the same period as clock pulse and 1 state (time of one read or write cycle) consists of 4 clock pulses.

A write cycle is executed whenever the low level \overline{CE}_1 overlaps with the low level \overline{CS} at the last "H" → "L" edge of T_1 (first clock pulse of write cycle). The address is

determined by \overline{CAE}_0 , \overline{CAE}_1 and $A_0 \sim A_{17}$.

The data is latched into a cell on the last "H" → "L" edge of T_2 (second clock pulse of write cycle) requiring the set-up and hold time relative to this edge to be maintained.

A read cycle is executed whenever the low level \overline{CE}_2 overlaps with the low level \overline{CS} at the last "H" → "L" edge of T_1 . When address is determined by \overline{CAE}_0 , \overline{CAE}_1 and $A_0 \sim A_7$, data situated on the address is read.

When setting \overline{CS} at high level or \overline{CE}_1 and \overline{CE}_2 at the same time at high level, the chip is in a non-selectable mode in which both reading and writing are disabled. In this mode, the output stage is in floating state.

DESCRIPTION OF PINS

I/O	Symbol	Function																								
	RESET	Reset input This input resets built-in flip flop and is active H.																								
	CLK	Clock input																								
	\overline{CS} \overline{CE}_1 , \overline{CE}_2	Decode signal of CPU address Status signal from CPU The memory access cycle is started by \overline{CS} , \overline{CE}_1 and \overline{CE}_2 signals. <table border="1" style="margin: 10px auto;"> <thead> <tr> <th>\overline{CS}</th> <th>\overline{CE}_1</th> <th>\overline{CE}_2</th> <th>Mode</th> </tr> </thead> <tbody> <tr> <td>H</td> <td>Don't care</td> <td>Don't care</td> <td>No-access</td> </tr> <tr> <td>L</td> <td>L</td> <td>L</td> <td>Read</td> </tr> <tr> <td>L</td> <td>L</td> <td>H</td> <td>Write</td> </tr> <tr> <td>L</td> <td>H</td> <td>L</td> <td>Read</td> </tr> <tr> <td>L</td> <td>H</td> <td>H</td> <td>No-access</td> </tr> </tbody> </table>	\overline{CS}	\overline{CE}_1	\overline{CE}_2	Mode	H	Don't care	Don't care	No-access	L	L	L	Read	L	L	H	Write	L	H	L	Read	L	H	H	No-access
\overline{CS}	\overline{CE}_1	\overline{CE}_2	Mode																							
H	Don't care	Don't care	No-access																							
L	L	L	Read																							
L	L	H	Write																							
L	H	L	Read																							
L	H	H	No-access																							
	\overline{OE}	Read signal from CPU (assumed that read cycle finish)																								
	R/W	Write signal from CPU (assumed that write cycle finish)																								
	\overline{CAE}_0 \overline{CAE}_1	Determine the valid combination of CAS \overline{CAS} is output by active L. <table border="1" style="margin: 10px auto;"> <thead> <tr> <th>\overline{CAE}_0</th> <th>\overline{CAE}_1</th> <th>Access area</th> </tr> </thead> <tbody> <tr> <td>H</td> <td>H</td> <td>—</td> </tr> <tr> <td>L</td> <td>H</td> <td>DQ₀~7</td> </tr> <tr> <td>H</td> <td>L</td> <td>DQ₈~15</td> </tr> <tr> <td>L</td> <td>L</td> <td>DQ₀~15</td> </tr> </tbody> </table>	\overline{CAE}_0	\overline{CAE}_1	Access area	H	H	—	L	H	DQ ₀ ~7	H	L	DQ ₈ ~15	L	L	DQ ₀ ~15									
\overline{CAE}_0	\overline{CAE}_1	Access area																								
H	H	—																								
L	H	DQ ₀ ~7																								
H	L	DQ ₈ ~15																								
L	L	DQ ₀ ~15																								
	$A_0 \sim A_{17}$	Address signal																								
Output	RDY	Read signal to CPU																								
Input	DQ ₀ ~15	Data input/output signal																								

4194304-BIT(262144-WORD BY 16-BIT)PSEUDO-PSEUDO STATIC RAM**ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Condition	Ratings	Unit
V_{CC}	Supply voltage		-0.5 ~ 7.0	V
V_I	Input voltage	With respect to V_{SS}	-0.5 ~ $V_{CC} + 0.5$	V
V_O	Output voltage		-0.5 ~ $V_{CC} + 0.5$	V
I_{IK}	Input protection diode current	$V_I < 0V$	-20	mA
		$V_I > V_{CC}$	+20	
I_O	Output current		50	mA
P_d	Power dissipation	$T_a = 25^\circ C$	5500	mW
T_{opr}	Operating temperature		0 ~ 70	$^\circ C$
T_{stg}	Storage temperature		-40 ~ 125	$^\circ C$

RECOMMENDED OPERATING CONDITIONS ($T_a = 0 \sim 70^\circ C$, unless otherwise noted) (Note 2)

Symbol	Parameter	Limits			Unit
		Min	Typ	Max	
V_{CC}	Supply voltage	4.5	5	5.5	V
V_{SS}	Supply voltage		0		V
V_I	Input voltage	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	V

Note 2: All voltage values are with respect to V_{SS} .

ELECTRICAL CHARACTERISTICS ($T_a = 0 \sim 70^\circ C$, $V_{CC} = 5V \pm 10\%$, $V_{SS} = 0V$, unless otherwise noted) (Note 3)

Symbol	Parameter	Test conditions	Limits			Unit	
			Min	Typ	Max		
V_{T+}	Threshold voltage (RESET)	$V_O = 0.1, V_{CC} - 0.1V, I_O = 20\mu A$			2.4	V	
V_{T-}	Threshold voltage (RESET)	$V_O = 0.1, V_{CC} - 0.1V, I_O = 20\mu A$	0.6			V	
$V_{T+} - V_{T-}$	Hysteresis width (RESET)	$V_O = 0.1, V_{CC} - 0.1V, I_O = 20\mu A$	0.2		1.8	V	
V_{IH}	High input voltage (other input)	$V_O = 0.1, V_{CC} - 0.1V, I_O = 20\mu A$	2.0			V	
V_{IL}	Low input voltage (other input)	$V_O = 0.1, V_{CC} - 0.1V, I_O = 20\mu A$			0.4	V	
V_{OH}	High output voltage	$I_{OH} = -5mA$	2.4		V_{CC}	V	
V_{OL}	Low output voltage	$I_{OL} = 4.2mA$	0		0.4	V	
I_{IH}	High input current	$V_I = V_{CC}$			1.0	μA	
I_{IL}	Low input current	$V_I = GND$			1.0	μA	
$I_{CC1(AV)}$	Average supply current from operating (Note 4, 5)	MH25616PNA-10	Maximum repeating frequency, output open			240	mA
		MH25616PNA-12				200	
$I_{CC2(1)}$	Average supply current from V_{CC} , stand by	$V_I = 2.4V, 0.4V$, Output open (Note 6)			16.7	mA	
$I_{CC2(2)(AV)}$		$V_I = V_{CC}, GND, f = 10MHz$ Output open (Note 4, 7)			3.5	mA	
$I_{CC2(AV)}$	Average supply current from V_{CC} , CAS before RAS refreshing (Note 4)	MH25616PNA-10	Refresh cycling, output open			240	mA
		MH25616PNA-12	(5 clock from 117th clock)			220	
$C_{I(A)}$	Input capacitance, address inputs				15	pF	
C_I	Input capacitance (except address inputs)	$V_I = V_{SS}, f = 1MHz$			15	pF	
$C(DQ)$	Input/output capacitance, Data input/output inputs	$V_I = 25mVrms$			17	pF	
$C_O(RDY)$	Output capacitance, RDY inputs	$V_O = V_{SS}, f = 1MHz, V_I = 25mVrms$			10	pF	

Note 3: Current flowing into IC is positive, out is negative.

4: $I_{CC1(AV)}$, $I_{CC2(2)(AV)}$, $I_{CC3(AV)}$ are dependent on frequency of clock pulse. Limits are measured at maximum frequency.

5: $I_{CC1(AV)}$ is dependent on output loading specified values are obtained with the output open.

6: Only one input set to this value, all other input fix V_{CC} or GND.

7: The value is setting to I_{CC3} , when it get in refresh cycle every 121 clock.

MH25616PNA-10,-12

4194304-BIT(262144-WORD BY 16-BIT)PSEUDO-PSEUDO STATIC RAM

SWITCHING CHARACTERISTICS (Ta=0~70°C, VCC=5V±10%, VSS=0V, unless otherwise noted) (Note 8)

Symbol	Parameter	Limits						Unit
		MH25616PNA-10			MH25616PNA-12			
		Min	Typ	Max	Min	Typ	Max	
f	Repeating frequency	7.8		11.1	7.8		9.95	MHz
t _{PLH}	CLK, \overline{OE} , R/W-RDY propagation time (Note 9)			36			36	ns
t _{PHL}				36			36	ns
t _{CKA}	CLK access time			136			156	ns
t _{OFF}	Output disable time after \overline{OE} high	40		65	40		70	ns

Note 8: After power-up an initial pause of 500μs and dummy cycle (Read or Write cycle by 8 times degrees) followed by CLK, \overline{CS} , \overline{CE}_1 , \overline{CE}_2 , \overline{OE} , R/W cycles are required before proper device operation is achieved. It may add that cycle during the initial pause, but dummy cycle is required.

9: The values are measured at loading capacitance C_L = 50pF.

TIMING REQUIREMENTS (Ta=0~70°C, VCC=5V±10%, VSS=0V, unless otherwise noted) (Note 10, 11)

Read, Write, Refresh Mode Cycle

Symbol	Parameter	Limits						Unit
		MH25616PNA-10			MH25616PNA-12			
		Min	Typ	Max	Min	Typ	Max	
t _{CKL}	CLK low pulse width	40		75	45		70	ns
t _{CKH}	CLK high pulse width	40		75	45		70	ns
t _{CSS}	CLK- \overline{CS} setup time	20			20			ns
t _{CSh}	CLK- \overline{CS} hold time	20			20			ns
t _{CE1S}	CLK- \overline{CE}_1 setup time	20			20			ns
t _{CE1H}	CLK- \overline{CE}_1 hold time	20			20			ns
t _{CE2S}	CLK- \overline{CE}_2 setup time	20			20			ns
t _{CE2H}	CLK- \overline{CE}_2 hold time	20			20			ns
t _{OES}	CLK- \overline{OE} setup time	20			20			ns
t _{OEH}	CLK- \overline{OE} hold time	1.5CK+10		2.5CK-20	1.5CK+10		2.5CK-20	ns
t _{RWS}	CLK-R/W setup time	20			20			ns
t _{RWH}	CLK-R/W hold time	1.0CK+10		2.0CK-20	1.0CK+10		2.0CK-20	ns
t _{AS}	CLK-ADDRESS setup time	20			20			ns
t _{AH}	CLK-ADDRESS hold time (READ) CLK-ADDRESS hold time (WRITE)	55			55			ns
		0.5CK+55			0.5CK+55			
t _{CAS}	CLK- \overline{CAE} setup time	20			20			ns
t _{CAH}	CLK- \overline{CAE} hold time	20			20			ns
t _{DS}	CLK-DATA setup time	0			0			ns
t _{DH}	CLK-DATA hold time	55			60			ns
t _T	Transition time (Note 12)	3		50	3		50	ns
t _{REF}	Refresh cycle time (every 121 clocks)	10.9		15.7	12.1		15.7	μs

Note 10: The timing requirements are assumed t_T = 5ns.

11: V_I = 1.3V is reference levels for measuring timing of input signals.

12: t_T is measured between V_{IH(min)} and V_{IL(max)}.

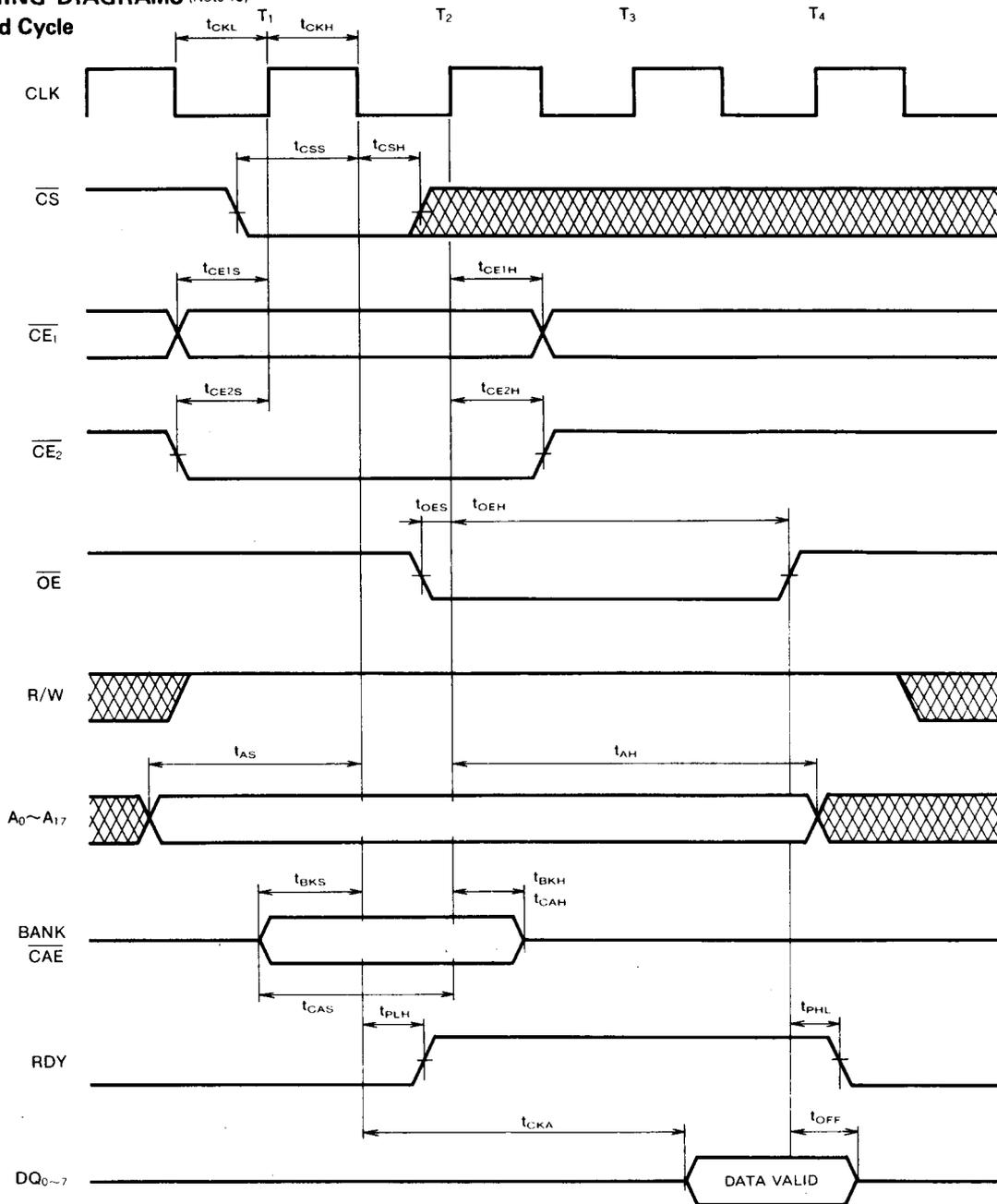
Reset-Mode-Cycle

Symbol	Parameter	Limits						Unit
		MH25616PNA-10			MH25616PNA-12			
		Min	Typ	Max	Min	Typ	Max	
t _{REW}	RESET pulse width	20			20			ns
t _{REC}	CLK-RESET recovery time	20			20			ns

4194304-BIT(262144-WORD BY 16-BIT)PSEUDO-PSEUDO STATIC RAM

TIMING DIAGRAMS (Note 13)

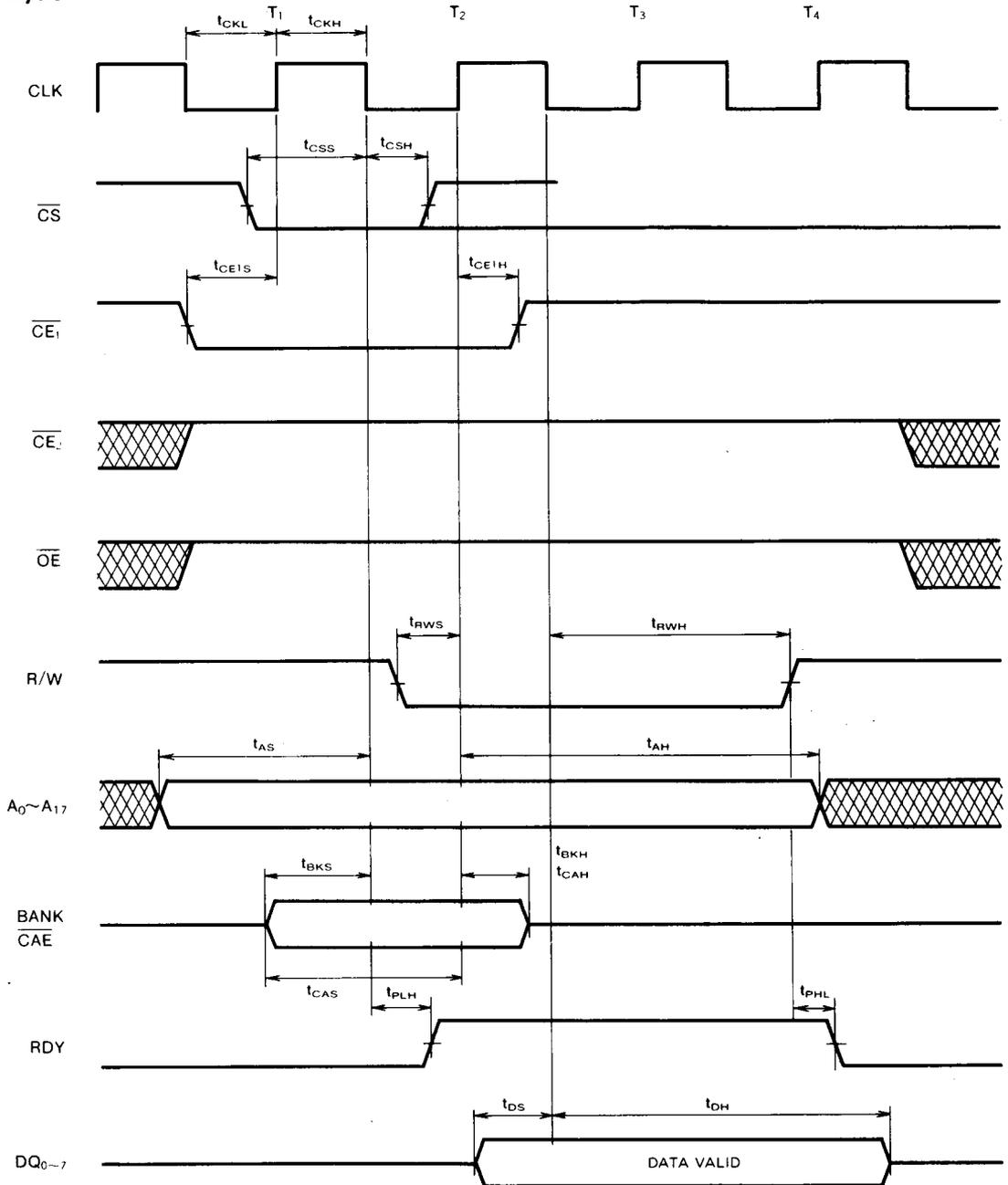
Read Cycle



Note 13  Indicates the don't care input.

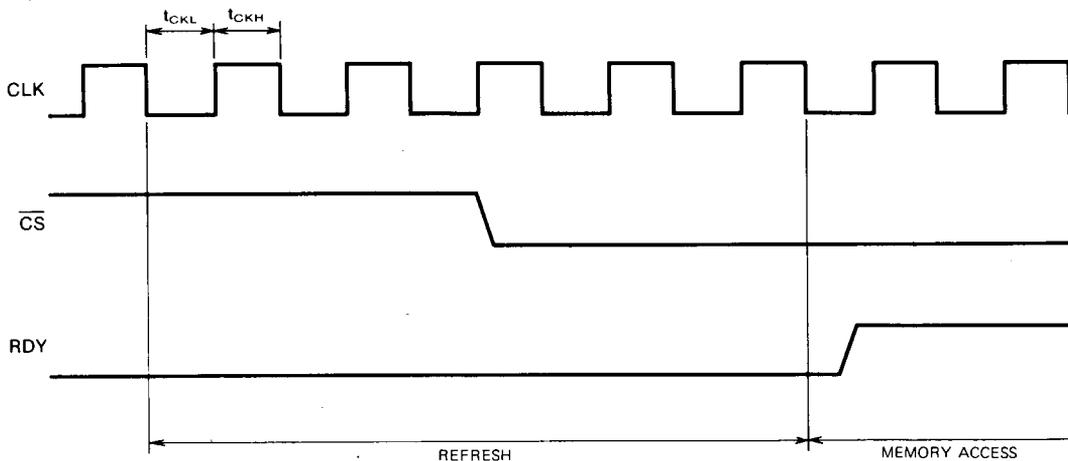
4194304-BIT(262144-WORD BY 16-BIT)PSEUDO-PSEUDO STATIC RAM

Write Cycle



4194304-BIT(262144-WORD BY 16-BIT)PSEUDO-PSEUDO STATIC RAM

Refresh Cycle (Note 14)



Note 14: While refresh cycle, other input signal are waiting condition.

Reset Cycle

